

RELIABILITY PHYSICS

N87-16441

LEAKAGE-CURRENT PROPERTIES OF ENCAPSULANTS

JET PROPULSION LABORATORY

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Study Objectives

- Establish reliability assessment methodology associated with module leakage current
 - Leakage current conduction model
 - Dynamic simulation of charge transfer in field conditions
 - Module design considerations
 - Accelerated chamber testing

- Establish leakage-current properties of encapsulant materials
 - Characteristics of ionic conductivity
 - Material property degradation
 - Recommendations for future investigations

Approach

- Quantify basic encapsulant properties associated with module leakage currents
 - Sorption isotherms
 - Ionic conductivities

- Develop generic models of module conduction including:
 - Bulk conduction
 - Surface conduction
 - Interface conduction

- Conduct sensitivity studies of relevant parameters

- Perform simulation analyses of leakage currents and charge transfer in field environments

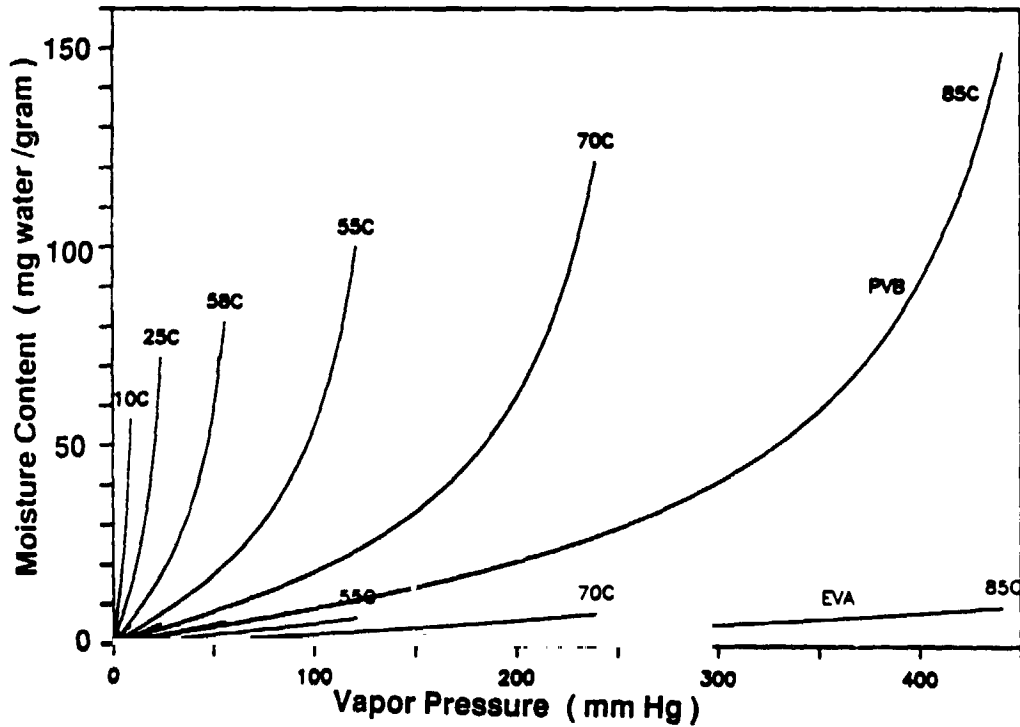
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Water Vapor Sorption

- Sorption isotherms for pristine materials
 - Temperature/humidity
 - Manufacturing process
 - Lamination/curing process
- Thermal degradation
 - Severe plasticizer loss for PVB
 - Negligible effect on EVA
- Hydrolysis
 - Significant increase in water sorption capacity of EVA and PVB after exposure in high temperature, high humidity environments

Water Sorption Isotherms



Bulk Conductivity: Theory

- Sensitive to both temperature and humidity level

$$K_V = M_V \text{Exp} [(-E_0/RT)(Z_p/Z_w)^C]$$

E_0 = Activation energy

Z_p, Z_w = permittivity of polymer and water

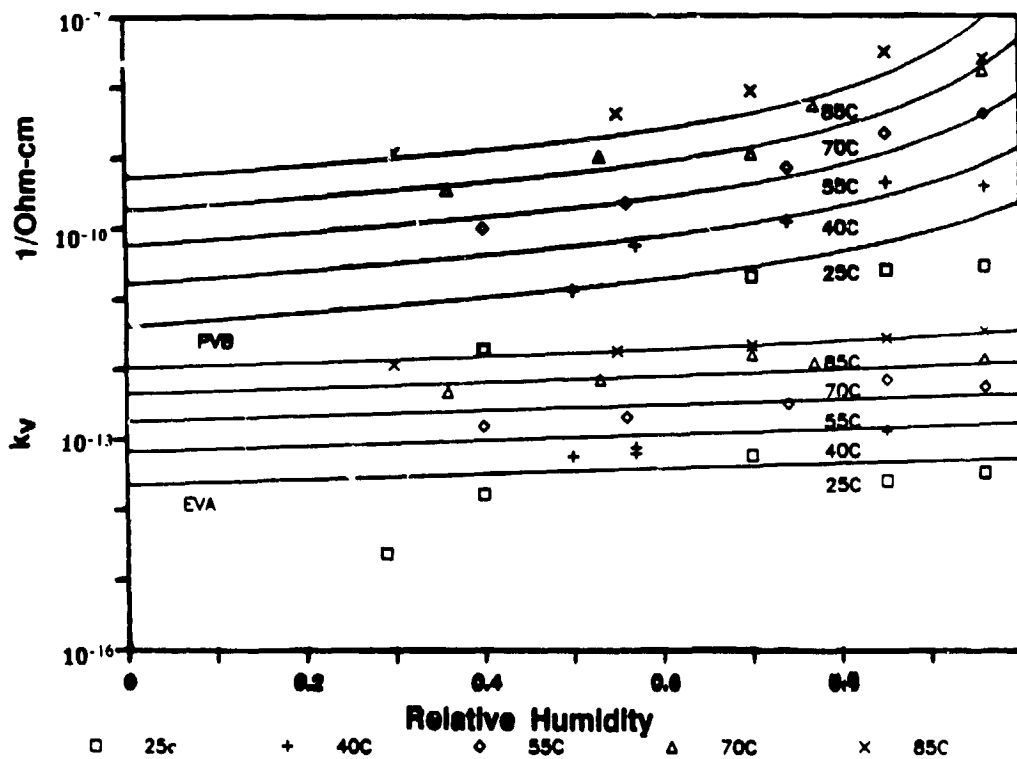
R = Gas constant

T = Temperature (in absolute scale)

C = Moisture concentration

M_V = property constant

Bulk Conductivity: Measurements



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Surface and Interface Conductivities: Theory

- Polymer surfaces

$$K_S = M_S \text{ Exp } [(-E_S/RT)(1 - RH\{ 1 - (Z_p/Z_w)\})]$$

- Glass surfaces

$$K_S = M_S \text{ Exp } [(-E_S/RT)(1 - y RH\{ 1 - (Z_g/Z_w)\})]$$

RH = Relative humidity

y = SURFACE MOISTURE factor

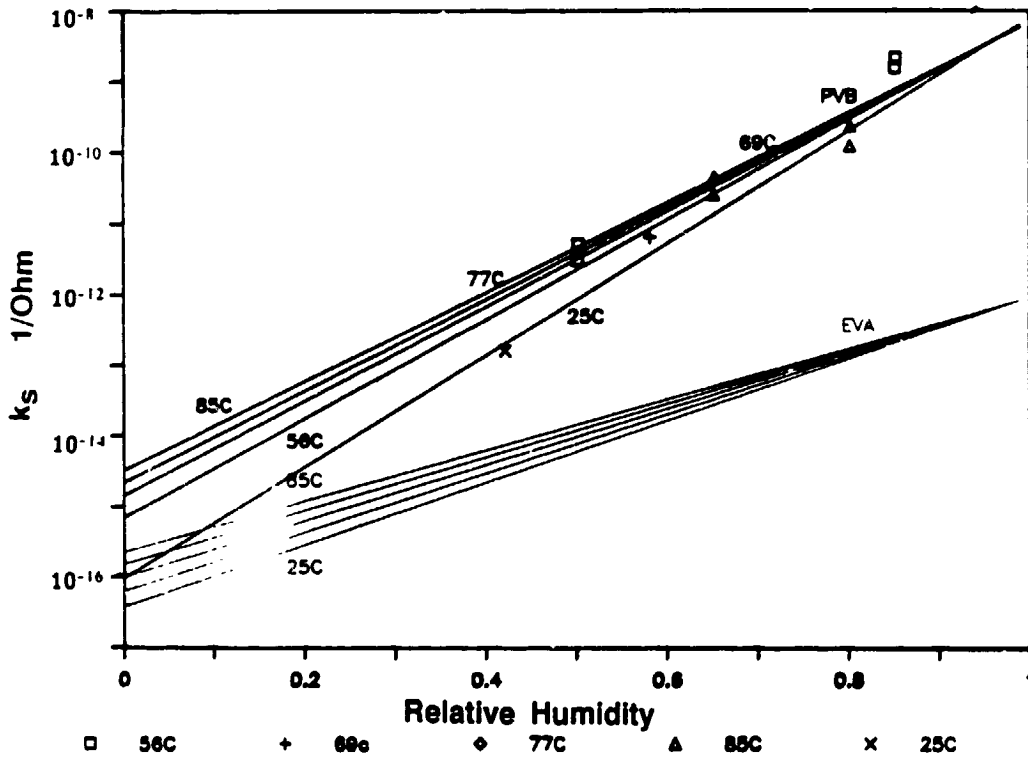
Z_g = permittivity of glass

- Interfaces

$$K_i = K_{S1} + K_{S2}$$

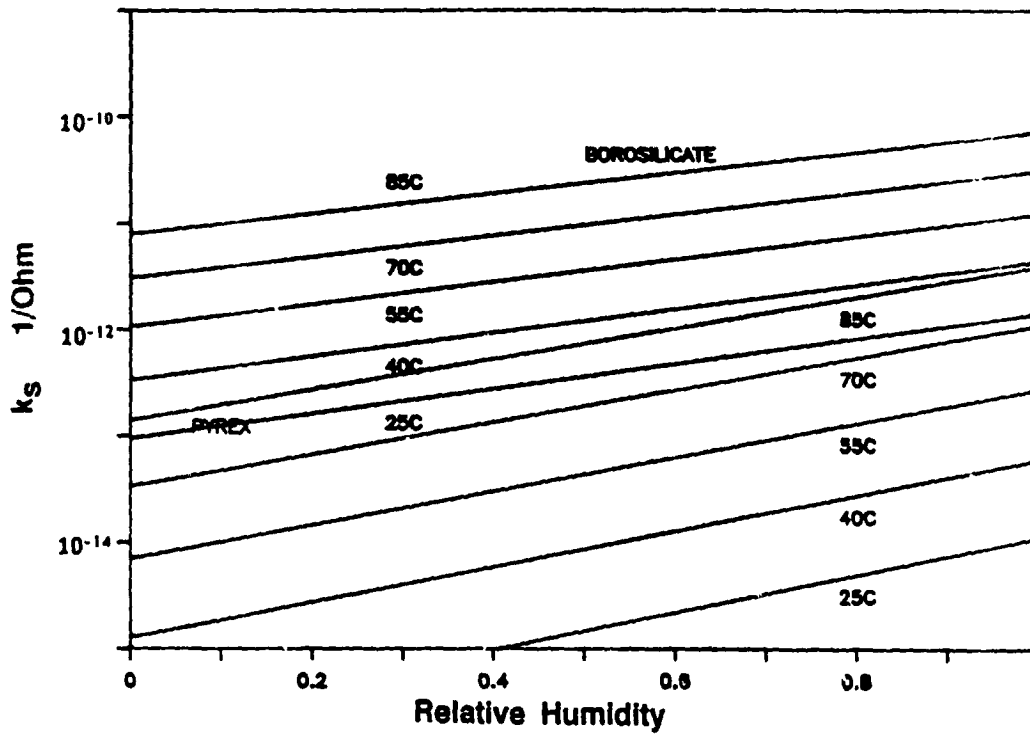
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Surface Conductivity: PVB and EVA at Various Relative Humidities and Temperatures

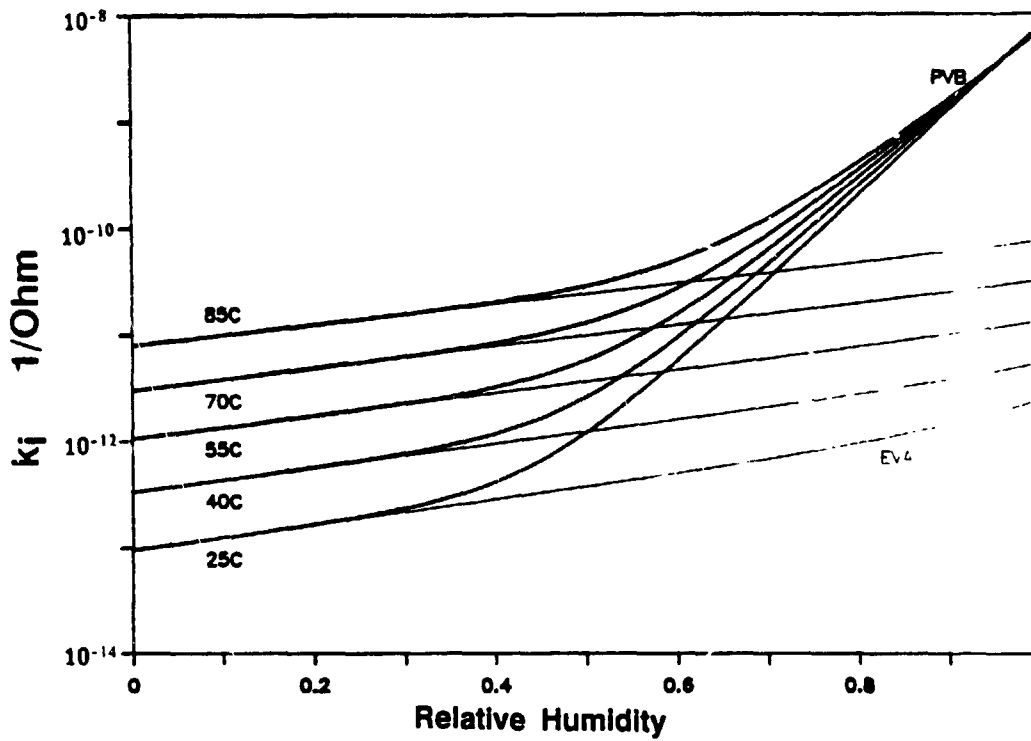


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Surface Conductivity: Borosilicate and Pyrex Glasses at Various Relative Humidities and Temperatures



Interface Conductivity: Measurements of PVB and EVA

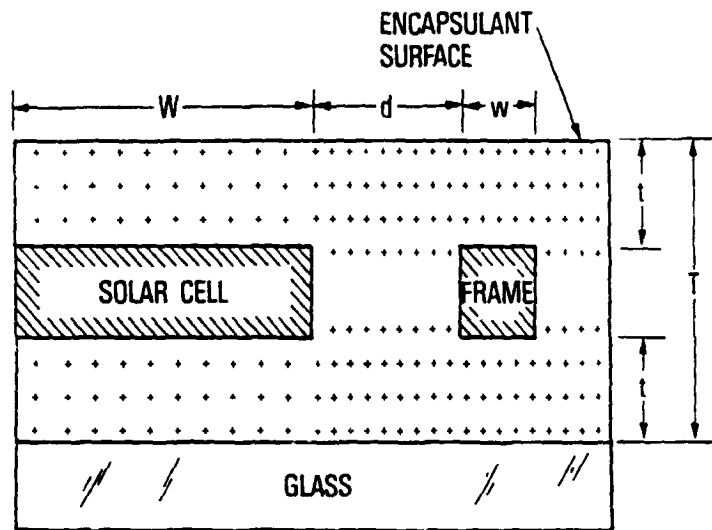


Leakage-Current Simulation

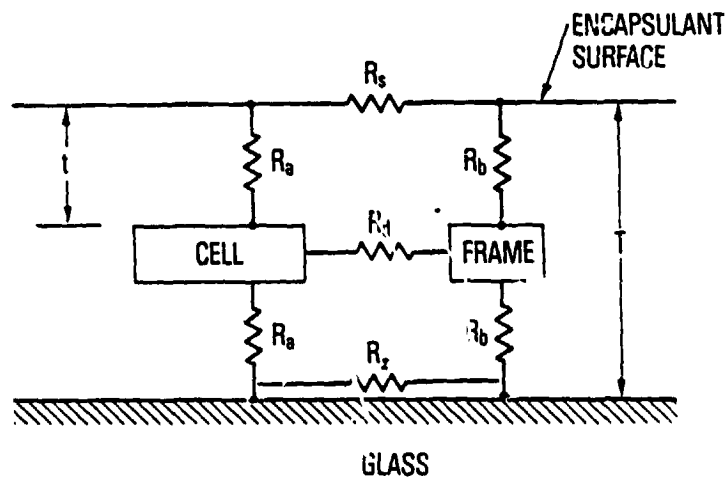
- 2-dimensional ionic conduction model
- Composite conductive paths
- Parametric study of the interplay of bulk, surface and interface conductivities
- Comparison with experimental results

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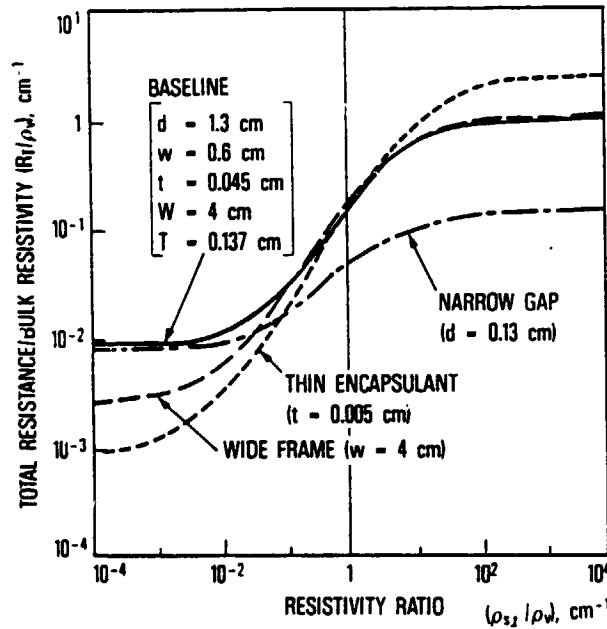
Cross-Sectional View of Test Coupons



Network Conduction Model



Ionic Conduction Characteristics

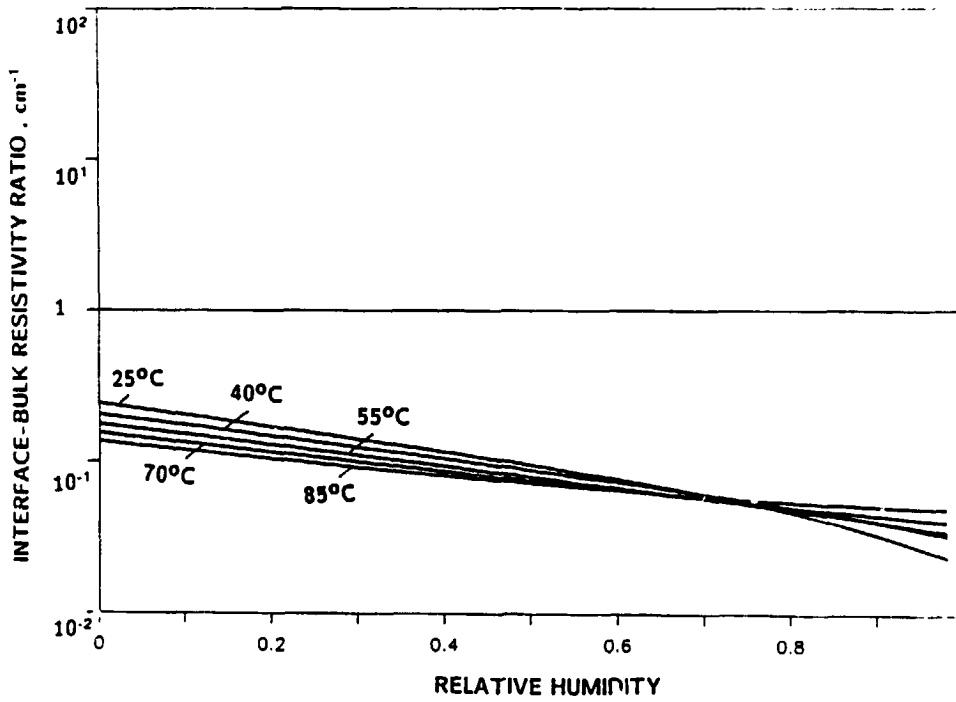


Ionic Conductivities and Their Temperature-Humidity Sensitivities

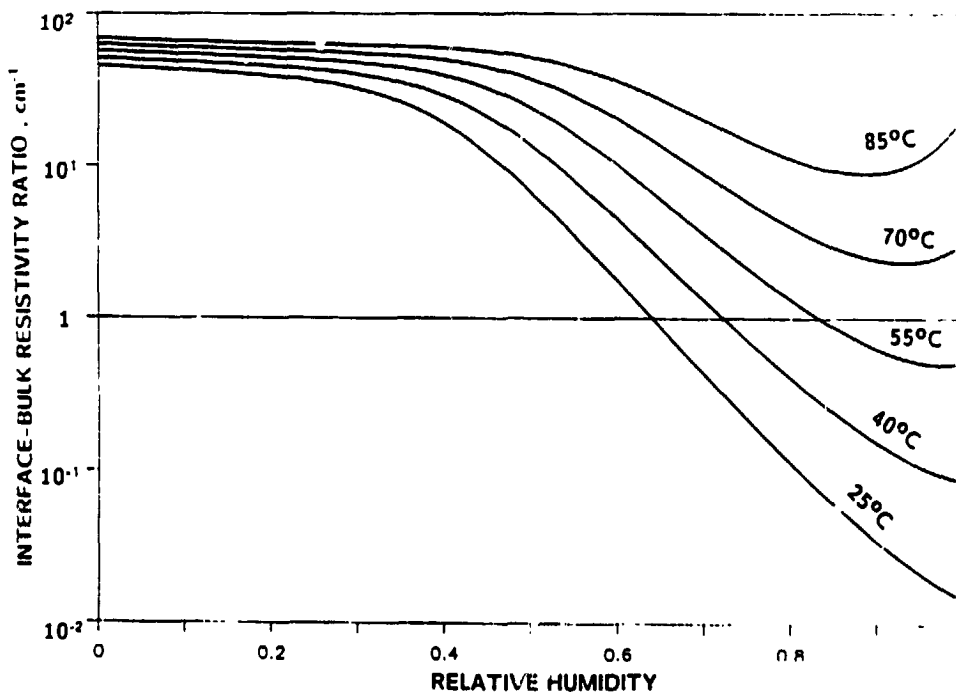
	Magnitude	Temperature sensitivity	Humidity sensitivity
• Bulk encapsulants			
• PVB	High	High	High
• EVA	Low	Modest	Low
• Encapsulant free surface			
• PVB	High	Very low	High
• EVA	Very low	Low	Modest
• Encapsulant-glass interface			
• PVB	High	Low	High
• EVA	Modest	Modest	Modest

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EVA Resistivity Ratio



PVB Resistivity Ratio



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Leakage-Current Sensitivity

- Exposed low-conductivity encapsulant (EVA)
 - Key contributor to module leakage-resistance is bulk resistivity of encapsulant between cell and interface
 - High temperature sensitivity
 - Low humidity sensitivity
- Exposed high-conductivity encapsulant (PVB)
 - Key contributors to module leakage resistance are resistivity of interfaces and free surfaces
 - Low temperature sensitivity
 - high humidity sensitivity
- Foil-protected encapsulant
 - Key contributor to module leakage-resistance is bulk resistivity of encapsulant between cell and foil
 - High temperature sensitivity
 - Humidity sensitivity depends on edge seal

Summary

- Have achieved fairly good fundamental understanding of leakage-current paths internal to module and their temperature-humidity sensitivities
- Evaluation of the acceleration factor between test chamber and field condition is a very complex process
- Research areas
 - Effect of liquid water versus water vapor
 - Effect of polymer aging on encapsulant sorption-conductivity properties
 - Non-isothermal and non-equilibrium conditions
 - Transient permeation of moisture
 - Non-equilibrium moisture states